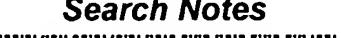


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/816,266	HOLBERG ET AL.
	Examiner	Art Unit
	Hiep Nguyen	2816

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner